

TEST REPORT

FCC ID: 2ADINN5001TL

Product: LTE mobile phone

Model No.: N5001L

Additional Model No.: N5001TL, A4L, A3L

Trade Mark: NUU

Report No.: TCT171020E012

Issued Date: Oct. 20, 2017

Issued for:

Sun Cupid Technology (HK) Ltd.

16/F, CEO Tower, 77 Wing Hong St, Cheung Sha Wan, Kowloon, Hong Kong.

Issued By:

Shenzhen Tongce Testing Lab.

1B/F., Building 1, Yibaolai Industrial Park, Qiaotou, Fuyong, Baoan District, Shenzhen, Guangdong, China

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1. Test Certification

Product:	LTE mobile phone		
Model No.:	N5001L		
Additional Model:	N5001TL, A4L, A3L		
Trade Mark:	NUU		
Applicant:	Sun Cupid Technology (HK) Ltd.		
Address:	16/F, CEO Tower, 77 Wing Hong St, Cheung Sha Wan, Kowloon, Hong Kong.		
Manufacturer:	SUNCUPID (ShenZhen) Electronic Ltd		
Address:	Baolong Industrial City, Longgang District, Shenzhen Hi-Tech Road, Building 1, A 7, China.		
Date of Test:	Apr. 24, 2017 – Sep. 30, 2017		
Applicable Standards:	FCC CFR Title 47 Part 2 FCC CFR Title 47 Part22 FCC CFR Title 47 Part24 FCC CFR Title 47 Part27		

The above equipment has been tested by Shenzhen Tongce Testing Lab. and found compliance with the requirements set forth in the technical standards mentioned above. The results of testing in this report apply only to the product/system, which was tested. Other similar equipment will not necessarily produce the same results due to production tolerance and measurement uncertainties.

Tested By:

Garen

Tomsin

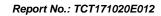
Date: Sep. 30, 2017

Reviewed By:

Date: Oct. 20, 2017

Approved By:

Date: Oct. 20, 2017



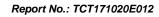


2. Test Result Summary

Requirement	CFR 47 Section	Result
Conducted Output Power	§2.1046; §24.232(c); §27.50(h); §27.50(c); §27.50(d); §22.913	PASS
Peak-to-Average Ratio	§24.232(d); §22.913; §27.50	PASS
Effective (Isotropic) Radiated Power	§2.1046; §24.232(c); §27.50(h); §27.50(c); §27.50(d); §22.913	PASS
Occupied Bandwidth	§2.1049; §24.238(b); §27.53(h)(3); §27.53(m)(6);	PASS
Band Edge	§2.1051; §27.53(g); §27.53(h); §24.238(a); §22.917(a); §27.53(m);	PASS
Conducted Spurious Emission	§2.1051; §27.53(g); §27.53(h); §24.238(a); §22.917(a); §27.53(m);	PASS
Field Strength of Spurious Radiation	§2.1053; §27.53(g); §27.53(h); §24.238(b); §22.917(a); §27.53(m);	PASS
Frequency Stability for Temperature & Voltage	§2.1055;§27.54; §24.235; §22.355	PASS

Note:

- 1. PASS: Test item meets the requirement.
- 2. Fail: Test item does not meet the requirement.
- 3. N/A: Test case does not apply to the test object.
- 4. The test result judgment is decided by the limit of test standard.





3. EUT Description

Product: LTE mobile phone			
Model No.:	N5001L		
Additional Model:	N5001TL, A4L, A3L		
Trade Mark:	NUU		
Hardware version:	110SFM788P0A2V0		
Software version:	N5001L-AM-01		
Tx Frequency:	LTE Band 2: 1850 MHz ~ 1910 MHz LTE Band 4: 1710 MHz ~ 1755 MHz LTE Band 5: 824 MHz ~ 849 MHz LTE Band 7: 2500 MHz ~ 2570 MHz LTE Band 12: 699 MHz ~ 716 MHz LTE Band 17: 704 MHz ~ 716 MHz		
Rx Frequency:	LTE Band 2: 1930 MHz ~ 1990 MHz LTE Band 4: 2110 MHz ~ 2155 MHz LTE Band 5: 869 MHz ~ 894 MHz LTE Band 7: 2620 MHz ~ 2690 MHz LTE Band 12: 729 MHz ~ 746 MHz LTE Band 17: 734 MHz ~ 746 MHz		
Bandwidth:	LTE Band 2: 1.4MHz /3MHz /5MHz /10MHz /15MHz / 20MHz LTE Band 4: 1.4MHz /3MHz /5MHz /10MHz /15MHz / 20MHz LTE Band 5: 1.4MHz /3MHz /5MHz /10MHz LTE Band 7: 5MHz /10MHz /15MHz / 20MHz LTE Band 12: 1.4MHz /3MHz /5MHz /10MHz LTE Band 17: 5MHz /10MHz		
Maximum Output Power to Antenna:	LTE Band 2: 21.60dBm LTE Band 4: 21.27dBm LTE Band 5: 21.80dBm LTE Band 7: 21.54dBm LTE Band 12: 21.98dBm LTE Band 17: 21.99dBm		
99% Occupied Bandwidth:	LTE Band 2: 18M2G7D LTE Band 4: 18M2G7D LTE Band 5: 9M12G7D LTE Band 7: 18M2W7D; 18M2G7D LTE Band 12: 9M12W7D LTE Band 17: 9M04W7D; 9M04G7D		
Type of Modulation:	QPSK / 16QAM		
Antenna Type:	Internal Antenna		



	LTE Band 2: 0.49dBi	
	LTE Band 4: 0.48dBi	
	LTE Band 5: -0.52dBi	
Antenna Gain:	LTE Band 7: 0.50dBi	
	LTE Band 12: 0.58dBi	
	LTE Band 17: 0.57dBi	
Power Supply:	Rechargeable Li-ion Battery DC3.8V / 2000mAh	
	Adapter Information:	
	Model name: HJ-0501000E1-US	
Adapter:	Input: AC 100-240V 50/60Hz 0.2A	
	Output: DC 5.0V===1000mA	
Remark:	All models above are identical in interior structure, electrical	
	circuits and components, and just model names and color	
	are different for the marketing requirement.	
1 6 1	9 1	

Note: The report LTE band2/4/5/7 data is used in 2ADINN5001L reported test data.





4. Genera Information

4.1. Test environment and mode

Operating Environment:				
Temperature:	24.0 °C			
Humidity:	54 % RH			
Atmospheric Pressure:	1010 mbar			
Test Mode:				
Operation mode:	Keep the EUT in continuous transmitting with modulation			

The sample was placed 0.8m above the ground plane of 3m chamber. Measurements in both horizontal and vertical polarities were performed. During the test, each emission was maximized by: having the EUT continuously working, investigated all operating modes, rotated about all 3 axis (X, Y & Z) and considered typical configuration to obtain worst position, manipulating interconnecting cables, rotating the turntable, varying antenna height from 1m to 4m in both horizontal and vertical polarizations. The emissions worst-case are shown in Test Results of the following pages.



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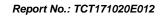


Description Operation Frequency

Test channels:

LTE BAND 2			
BW(MHz)	UL Channel	Frequency(MHz)	
1.4	18607	1850.7	
3	18615	1851.5	
5	18625	1852.5	
10	18650	1855	
15	18675	1857.5	
20	18700	1860	
1.4/3/5/10	40000	4000	
15 /20	18900	1880	
1.4	19193	1909.3	
3	19185	1908.5	
5	19175	1907.5	
10	19150	1905	
15	19125	1902.5	
20	19100	1900	
	BW(MHz) 1.4 3 5 10 15 20 1.4/3/5/10 15 /20 1.4 3 5 10 15	BW(MHz) UL Channel 1.4 18607 3 18615 5 18625 10 18650 15 18675 20 18700 1.4/3/5/10 18900 15 /20 19193 3 19185 5 19175 10 19150 15 19125	

LTE BAND 4			
Test Channel	BW(MHz)	UL Channel	Frequency(MHz)
	1.4	19957	1710.7
	3	19965	1711.5
(, (, ')	5	19975	1712.5
Low Range	10	20000	1715
	15	20025	1717.5
	20	20050	1720
Mid Range	1.4/3/5/10/15/20	20175	1732.5
-	1.4	20393	1754.3
	3	20385	1753.5
	5	20375	1752.5
High Range	10	20350	1750
	15	20325	1747.5
	20	20300	1745





LTE BAND 5				
Test Channel	BW(MHz)	UL Channel	Frequency(MHz)	
	1.4	20470	824.7	
_	3	20415	825.5	
Low Range	5	20425	826.5	
	10	20450	829	
Mid Range	1.4/3/5/10	20525	836.5	
	1.4	20643	848.3	
	3	20635	847.5	
High Range	5	20625	846.5	
	10	20600	844	

LTE BAND 7				
Test Channel	BW(MHz)	UL Channel	Frequency(MHz)	
	5	20775	2502.5	
	10	20800	2505	
Low Range	15	20825	2507.5	
(60)	20	20850	2510	
Mid Range	5/10/15/20	21100	2535	
	5	21425	2567.5	
	10	21400	2565	
High Range	15	21375	2562.5	
	20	21350	2560	

LTE BAND 12			
Test Channel	BW(MHz)	UL Channel	Frequency(MHz)
	1.4	23017	699.7
Law Davis	3	23025	700.5
Low Range	5	23035	701.5
	10	23060	704
Mid Range	1.4/3/5/10	23095	707.5
	1.4	23173	715.3
	3	23165	714.5
High Range	5	23155	713.5
	10	23130	711



LTE BAND 17				
Test Channel	BW(MHz)	UL Channel	Frequency(MHz)	
Law Davis	5	23755	706.5	
Low Range	10	23780	709	
Mid Range	5/10	23790	710	
Lligh Dange	5	23825	713.5	
High Range	10	23800	711	

Note 1: both QPSK&16QAM modulation has been measured;

Note 2: The worst condition was recorded in the test report if no other modes test data.





4.2. Test Mode

All modes and data rates and positions were investigated.

Test modes are chosen to be reported as the worst case configuration below:

	Test Mode	
Band	Radiated TCs	Conducted TCs
LTE Band 2	QPSK Link (1.4MHz / 3MHz / 5MHz / 10MHz / 15MHz / 20MHz)	16QAM Link (1.4MHz / 3MHz / 5MHz / 10MHz / 15MHz / 20MHz)
LTE Band 4	QPSK Link (1.4MHz / 3MHz / 5MHz / 10MHz / 15MHz / 20MHz)	16QAM Link (1.4MHz / 3MHz / 5MHz / 10MHz / 15MHz / 20MHz)
LTE Band 5	QPSK Link (1.4MHz / 3MHz / 5MHz / 10MHz)	16QAM Link (1.4MHz / 3MHz / 5MHz / 10MHz)
LTE Band 7	QPSK Link (5MHz / 10MHz / 15MHz / 20MHz)	16QAM Link (5MHz / 10MHz / 15MHz / 20MHz)
LTE Band 12	QPSK Link (1.4MHz / 3MHz / 5MHz / 10MHz)	16QAM Link (1.4MHz / 3MHz / 5MHz / 10MHz)
LTE Band 17	QPSK Link (5MHz / 10MHz)	16QAM Link (5MHz / 10MHz)

Antenna port conducted and radiated test items were performed according to KDB 971168 D02 Power Meas. License Digital Systems v02r02 with maximum output power. Radiated measurements were performed with rotating EUT in different three orthogonal test planes to find the maximum emission.

Tool Home	DI		В	andwic	th (MH	lz)		Mod	ulation		RB#		Test Channel		
Test Items Band	1.4	3	5	10	15	20	QPSK	16QAM	1	Half	Full	L	М	Н	
	2	v	v	v	v	v	v	v	v	v	v	v	V	v	v
	4	v	v	v	v	v	v	v	v	v	v	v	v	v	v
Max. Output	5	v	v	v	v		5)	v	v	v	v	v	v	v	v
Power	7			v	v	v	v	v	v	v	v	v	v	v	v
1 0 1101	12	v	v	v	v			v	v	v	v	v	v	v	v
	17			V	v			v	V	v	v	v	v	v	v
	2	v	v	V	v	v	v	v	V	v	v	v	V	v	v
Barda (a Assessed	4	v	v	v	v	v	v	v	v	v	v	v	v	v	v
Peak-to-Average Ratio	5	v	v	v	v		3	v	v	v	v	v	v	v	v
Natio	7			v	v	v	v	v	v	v	v	v	v	v	v



	12	v	v	v	v			v	v	v	v	v	v	v	v
	17			v	v			v	v	Y	٧	v	v	v	V
	2	v	v	v	v	v	v	v	v	0		v	v	v	٧
	4	v	v	v	v	v	v	v	v			v	v	v	v
26dB and 99%	5	v	v	V	v			v	v			v	V	v	v
Bandwidth	7			V	V	v	v	v	9			V	V	v	v
	12	v	v	v	v			v	v			v	v	v	v
	17	-2.		v	v		Z\	v	v		X	v	v	v	v
		GN.				(,)				(,0					(,(

			R	andwid	ith (MF	lz)		Mod	ulation		RB#		Tes	t Chan	nel
Test Items	Band	1.4	3	5	10	15	20	QPSK	16QAM	1	Half	Full	L	М	н
	2	v	v	V	v	v	v	v	v	v		v	v		v
	4	v	v	v) _v	v	v	v	v	v		v	V		v
	5	v	v	v	v			v	v	v		v	v		ν
Conducted	7			v	v	v	v	v	v	v	-,.	v	v		v
Band Edge	12	v	v	v	v		(()	v	v	v	5)	v	v		v
	17			v	v			v	v	v		v	v		v
	2	v	v	v	v	v	v	v	ν	v			v	v	v
	4	v	v	v	v	v	v	v	6	v		(v	v	v
Conducted	5	v	v	V	v			v	v	v			v	v	v
Spurious 7 Emission 12	7			v	v	V	v	v	v	v			v	v	v
	12	v	v	v	v			v	v	v			v	V	v
	17			v	v			v	v	v			v	V	v
	2			(C)	v		<u> </u>	v	v		<u> </u>	v	(0)	v	1
	4				v			v	v			v		v	
-	5				v		-/.	v	v		-/-	v		v	
Frequency	7	O			v		(()	v	v		(C)	v		٧	
Stability	12				v			v	v			v		٧	
	17				v			v	v			v		٧	
	2	v	v	V	v	v	v	v (ν	v	v	v	v	v	ν
	4	v	v	v	v	v	v	v	v	v	v	v	v	v	v
	5	v	v	v	v			v	v	v	v	v	v	v	v
E.R.P./ E.I.R.P.	7			v	v	v	v	v	v	v	v	v	v	v	v
	12	v	v	v	v			v	v	v	v	v	v	v	v
	17			v	v			v	v	v	v	v	v	v	v



	2	v		v	v	v	v	v	v
	4	V		v	v	٧	v	v	V
Radiated Spurious	5	v		v	v	v	v	v	V
Emission	7		v	v	v	v	v	v	v
	12	v		v	V	v	v	٧	v
	17		v	v	v	v	V	v	v
N .	4 The		"	 Caralta a	l 4				

Note

- 1. The mark "v" means that this configuration is chosen for testing
- 2. The mark "-" means that this bandwidth is not supported.

4.3. Description of Support Units

The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

Equipment	Model No.	Serial No.	FCC ID	Trade Name

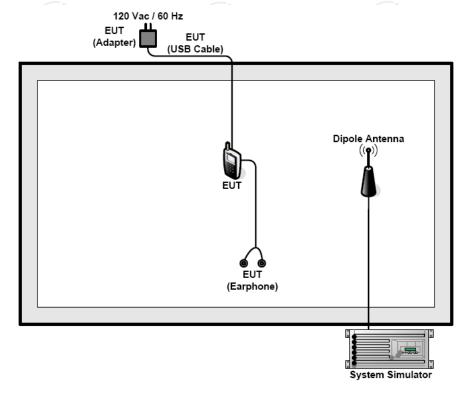
Note:

- 1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.
- 2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.





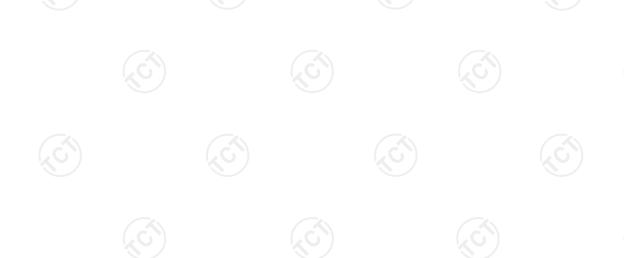
4.4. Configuration of Tested System



4.5. Measurement Results Explanation Example

For all conducted test items:

The offset level is set in the spectrum analyzer to compensate the RF cable loss and attenuator factor between RF conducted output port and spectrum analyzer. With the offset compensation, the spectrum analyzer reading level will be exactly the RF output level. The spectrum analyzer offset is derived from RF cable loss and attenuator factor. Offset = RF cable loss + attenuator factor.



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5. Facilities and Accreditations

5.1. Facilities

The test facility is recognized, certified, or accredited by the following organizations:

• FCC - Registration No.: 645098

Shenzhen Tongce Testing Lab.

The 3m Semi-anechoic chamber has been registered and fully described in a report with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files.

IC - Registration No.: 10668A-1

The 3m Semi-anechoic chamber of Shenzhen TCT Testing Technology Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing

5.2. Location

Shenzhen Tongce Testing Lab

Address: 1B/F., Building 1, Yibaolai Industrial Park, Qiaotou, Fuyong, Baoan District,

Shenzhen, Guangdong, China

TEL: +86-755-27673339

5.3. Measurement Uncertainty

The reported uncertainty of measurement $y \pm U$, where expended uncertainty U is based on a standard uncertainty multiplied by a coverage factor of k=2, providing a level of confidence of approximately 95 %.

No.	Item	MU
1	Conducted Emission	±2.56dB
2	RF power, conducted	±0.12dB
3	Spurious emissions, conducted	±0.11dB
4	All emissions, radiated(<1G)	±3.92dB
5	All emissions, radiated(>1G)	±4.28dB
6	Temperature	±0.1°C
7	Humidity	±1.0%



6. Test Results and Measurement Data

6.1. Conducted Output Power Measurement

6.1.1. Test Specification

Test Requirement:	FCC part 27.50(c), FCC part 27.50(d) and FCC part 27.50(h), FCC part 24.232(c), FCC part 22.913					
Test Method:	FCC part 2.1046					
Limits:	LTE Band 2: 2W LTE Band 4: 1W LTE Band 5: 7W LTE Band 7: 2W LTE Band 12: 1W LTE Band 17: 1W					
Test Setup:	System Simulator					
Test Procedure:	 The transmitter output port was connected to the system simulator. Set EUT at maximum power through system simulator. Select lowest, middle, highest channels for each band and different modulation. Measure and record the power level from the system simulator. 					
Test Result:	PASS					

6.1.2. Test Instruments

Equipment	Manufacturer	Model	Serial Number	Calibration Due
Wideband Radio Communication Tester	R&S	CMW500	114220	Jun. 12, 2018
RF cable (9kHz-40GHz)	TCT	RE-05	N/A	Sep. 27, 2018
Antenna Connector	TCT	RFC-02	N/A	Sep. 27, 2018



6.2. Peak to Average Ratio

6.2.1. Test Specification

Test Requirement:	FCC part 27.50, FCC part 24.232(d), FCC part 22.913
Test Method:	FCC KDB 971168 v02r02
Limit:	The peak-to-average ratio (PAR) of the transmission may not exceed 13 dB.
Test Setup:	System Simulator FUT Spectrum Analyzer
Test Procedure:	 The testing follows FCC KDB 971168 v02r02 Section 5.7.1. The EUT was connected to spectrum analyzer and system simulator via a power divider. Set EUT to transmit at maximum output power. Set the CCDF (Complementary Cumulative Distribution Function) option of the spectrum analyzer. Record the maximum PAPR level associated with a probability of 0.1%.
Test Result:	PASS

6.2.2. Test Instruments

Equipment	Manufacturer	Model	Serial Number	Calibration Due
Wideband Radio Communication Tester	R&S	CMW500	114220	Jun. 12, 2018
Spectrum Analyzer	ROHDE&SCH WARZ	FSQ	200061	Sep. 27, 2018
RF cable (9kHz-40GHz)	TCT	RE-05	N/A	Sep. 27, 2018
Antenna Connector	TCT	RFC-02	N/A	Sep. 27, 2018



6.3. 99% Occupied Bandwidth and 26dB Bandwidth Measurement

6.3.1. Test Specification

Test Requirement:	FCC part 27.53(h)(3) and FCC part 27.53(m)(6),					
rest Requirement.	FCC part 24.238(b), FCC part 2.1049					
Test Method:	FCC part 2.1049					
Limit:	N/A					
Test Setup:	System Simulator EUT Spectrum Analyzer					
Test Procedure:	 The testing follows FCC KDB 971168 v02r02 Section 4.2. The EUT was connected to the spectrum analyzer and system simulator via a power divider. The RF output of the EUT was connected to the spectrum analyzer by RF cable and attenuator. The path loss was compensated to the results for each measurement. The 99% occupied bandwidth were measured, set RBW= 1% of OBW, VBW= 3*RBW, sample detector, trace maximum hold. The 26dB bandwidth were measured, set RBW= 1% of EBW, VBW= 3*RBW, peak detector, trace maximum hold. 					
Test Result:	PASS					

6.3.2. Test Instruments

Equipment	Manufacturer	Model	Serial Number	Calibration Due
Wideband Radio Communication Tester	R&S	CMW500	114220	Jun. 12, 2018
Spectrum Analyzer	ROHDE&SCH WARZ	FSQ	200061	Sep. 27, 2018
RF cable (9kHz-40GHz)	TCT	RE-05	N/A	Sep. 27, 2018
Antenna Connector	TCT	RFC-02	N/A	Sep. 27, 2018



6.4. Band Edge and Conducted Spurious Emission Measurement

6.4.1. Test Specification

	FCC part 27.53(h), FCC part 27.53(g),			
Test Requirement:	FCC part 27.53(m)(4), FCC part 24.238(a),			
	FCC part22.917(a)			
Test Method:	FCC part2.1051			
Limit:	-13dBm			
Test Setup:	System Simulator Power Divider EUT Spectrum Analyzer			
Test Procedure:	 The testing follows FCC KDB 971168 v02r02 Section 6.0. The EUT was connected to the spectrum analyzer and system simulator via a power divider. The RF output of EUT was connected to the spectrum analyzer by an RF cable and attenuator. The path loss was compensated to the results for each measurement. The band edges of low and high channels for the highest RF powers were measured. The conducted spurious emission for the whole frequency range was taken. The RF fundamental frequency should be excluded against the limit line in the operating frequency band. The limit line is derived from 43 + 10log(P) dB below the transmitter power P(Watts) = P(W) - [43 + 10log(P)] (dB) = [30 + 10log(P)] (dBm) - [43 + 10log(P)] (dB) = -13dBm. For Band 17, he limit line is derived from 55 + 10log(P) dB below the transmitter power 			
Test Result:	PASS			



6.4.2. Test Instruments

	Equipment	Manufacturer	Model	Serial Number	Calibration Due	
	Wideband Radio Communication Tester	R&S	CMW500	114220	Jun. 12, 2018	
	Spectrum Analyzer	ROHDE&SCH WARZ	FSQ	200061	Sep. 27, 2018	
	RF cable (9kHz-40GHz)	тст	RE-05	N/A	Sep. 27, 2018	
)	Antenna Connector	тст	RFC-02	N/A	Sep. 27, 2018	

Note: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to international system unit (SI).

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6.5. Field Strength of Spurious Radiation Measurement

6.5.1. Test Specification

	FCC part 27.53(g) ,FCC part 27.53(h),				
Test Requirement:	FCC part 27.53(m)(4), FCC part 24.238(b)				
·	FCC part 22.917(a)				
Test Method:	FCC part 2.1053				
Limit:	30MHz~20GHz -13dBm				
	From 30MHz to 1GHz				
	RX Antenna				
	Ant. feed point 1~4 m Metal Full Soldered Ground Plane				
Test setup:	System Simulator Above 1GHz Ant. feed point Metal Full Soldered Ground Plane System Simulator Spectrum Analyzer / Receiver				
Test Procedure:	 The testing follows FCC KDB 971168 v02r02 Section 5.8 and ANSI / TIA-603-D-2010Section 2.2.12. The EUT was placed on a rotatable wooden table 0.8 meters above the ground. The EUT was set 3 meters from the receiving antenna, which was mounted on the antenna tower. The table was rotated 360 degrees to determine the position of the highest spurious emission. The height of the receiving antenna is varied between one meter and four meters to search for the maximum spurious emission for both horizontal and vertical 				



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		 polarizations. 6. Make the measurement with the spectrum analyzer's RBW = 1MHz, VBW = 3MHz, taking record of maximum spurious emission. 7. A horn antenna was substituted in place of the EUT and was driven by a signal generator. 8. Tune the output power of signal generator to the same emission level with EUT maximum spurious emission.
3		 9. Taking the record of output power at antenna port. 10. Repeat step 7 to step 8 for another polarization. 11. EIRP (dBm) = S.G. Power – Tx Cable Loss + Tx Antenna Gain 12. ERP (dBm) = EIRP - 2.15
		13. The RF fundamental frequency should be excluded against the limit line in the operating frequency band. 14. The limit line is derived from 43 + 10log(P) dB below the transmitter power P(Watts) = P(W) - [43 + 10log(P)] (dB) = [30 + 10log(P)] (dBm) - [43 + 10log(P)] (dB)

= -13dBm.

PASS

For Band 17, he limit line is derived from 55 + 10log(P) dB below the transmitter power

6.5.2. Test Instruments

Test results:

Radiated Emission Test Site (966)				
Name of Equipment	Manufacturer	Model	Serial Number	Calibration Due
System simulator	R&S	CMU200	111382	Sep. 27, 2018
Spectrum Analyzer	ROHDE&SCHW ARZ	R&S	FSQ	Sep. 27, 2018
Signal Generator	HP	83623B	3614A00396	Sep. 27, 2018
Broadband Antenna	Schwarzbeck	VULB9163	340	Sep. 27, 2018
Horn Antenna	Schwarzbeck	BBHA 9120D	631	Sep. 27, 2018
Broadband Antenna	Schwarzbeck	VULB9163	412	Sep. 27, 2018
Horn Antenna	Schwarzbeck	BBHA 9120D	1201	Mar. 05, 2018
Horn Antenna	Schwarzbeck	BBH 9170	582	Jun. 07, 2018
Dipole Antenna	тст	TCT-RF	N/A	Sep. 27, 2018
Coax cable (9kHz-1GHz)	тст	RE-low-01	N/A	Sep. 27, 2018



Coax cable (9kHz-40GHz)	тст	RE-high-02	N/A	Sep. 27, 2018
Coax cable (9kHz-1GHz)	тст	RE-low-03	N/A	Sep. 27, 2018
Coax cable (9kHz-40GHz)	ТСТ	RE-High-04	N/A	Sep. 27, 2018
Antenna Mast	Keleto	CC-A-4M	N/A	N/A
EMI Test Software	Shurple Technology	EZ-EMC	N/A	N/A





6.6. Frequency Stability Measurement

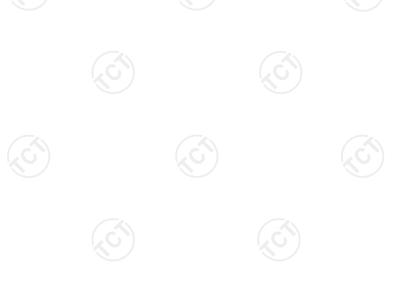
6.6.1. Test Specification

Test Requirement:	FCC part 27.54, FCC part 24.235, FCC Part 22.355			
Test Method:	FCC Part 2.1055			
Limit:	\pm 2.5 ppm			
Test Setup:	System Simulator Thermal Chamber			
Test Procedure:	 Test Procedures for Temperature Variation The testing follows FCC KDB 971168 v02r02 Section 9.0. The EUT was set up in the thermal chamber and connected with the system simulator. With power OFF, the temperature was decreased to -30°C and the EUT was stabilized before testing. Power was applied and the maximum change in frequency was recorded within one minute. With power OFF, the temperature was raised in 10°C steps up to 50°C. The EUT was stabilized at each step for at least half an hour. Power was applied and the maximum frequency change was recorded within one minute. Test Procedures for Voltage Variation The testing follows FCC KDB 971168 v02r02 Section 9.0. The EUT was placed in a temperature chamber at 25±5° C and connected with the system simulator. The power supply voltage to the EUT was varied from BEP to 115% of the nominal value measured at the input to the EUT. The variation in frequency was measured for the worst case. 			
Test Result:	PASS			



6.6.2. Test Instruments

Equipment	Manufacturer	Model	Serial Number	Calibration Due
Wideband Radio Communication Tester	R&S	CMW500	114220	Jun. 12, 2018
Programable tempratuce and humidity chamber	JQ	JQ-2000	N/A	Sep. 27, 2018
DC power supply	Kingrang	KR3005K 30V/5A	N/A	Sep. 27, 2018
RF cable (9kHz-40GHz)	ТСТ	RE-04	N/A	Sep. 27, 2018
Antenna Connector	TCT	RFC-03	N/A	Sep. 27, 2018





Appendix A: Photographs of Test Setup

Refer to test report TCT171020E013

Appendix B: Photographs of EUT

Refer to test report TCT171020E013

